

552. Title:TiSi<sub>2</sub> nanocrystal metal oxide semiconductor field effect transistor memory  
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Abstract:A TiSi<sub>2</sub> nanocrystal (NC) memory was fabricated. TiSi<sub>2</sub> NCs were synthesized on SiO<sub>2</sub> by annealing Ti covered Si NCs. Compared to the reference Si NC memory, both experiment and simulation results show that TiSi<sub>2</sub> NC memory exhibits larger memory window, faster writing and erasing, and longer retention lifetime as a result of the metallic property of the silicide NCs. Due to thermally stable, CMOS compatible properties, TiSi<sub>2</sub> NCs are highly promising for nonvolatile memory device application.